

Notice of References Cited

Application/Control No.

09/678,255

Applicant(s)/Patent Under
Reexamination
TANABE, MASAYUKI

Examiner

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Art Unit

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U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| | A | US-5,315,793 | 05-1994 | Peterson et al. | 451/2 |
| | B | US-5,146,098 | 09-1992 | Stack, Andrew P. | 250/492.2 |
| | C | US-4,155,651 | 05-1979 | Malone, Erle W. | 356/342 |
| | D | US-4,835,785 | 05-1989 | Thayer, William J. | 372/58 |
| | E | US-6,268,904 B1 | 07-2001 | Mori et al. | 355/53 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|-----------------|----------------|
| | N | WO 02/052345 A1 | 12-2002 | Japan | Shiraisi et al. | G03F 001/08 |
| | O | EP-0456202 A2 | 11-1991 | Europe | Kinney | G01N 21/53 |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | Wang BioMedical, dated 02/03/1998, http://wangbiomed.com/sclean.htm |
| | V | ORIEL Instruments, Optical Cleaning Supplies, http://www.oriel.com/netcat/Volumell/Descrpage/v3t6mat.htm |
| | W | Edmund Industrial Optics, The Importance of Cleaning Optics, http://www.edmundoptics.co ... upport/DisplayArticle.cfm?articleid=265 |
| | X | NASA Practice No. PD-ED-1233, Contamination Control Program |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.